

**Notice of References Cited**

Application/Control No.

10/783,522

Applicant(s)/Patent Under  
Reexamination  
LURIE ET AL.

Examiner

PABLO WHALEY

Art Unit

1631

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0091666	07-2002	Rice et al.	707/1
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
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**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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	Q					
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Yao et al., IEEE International Conference on Control Applications, Sept. 2000, p.1-21
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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